



FQB6N80 / FQI6N80

800V N-Channel MOSFET

General Description

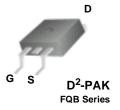
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

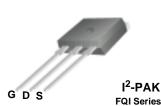
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supply.

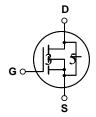
Features

- 5.8A, 800V, $R_{DS(on)} = 1.95\Omega @V_{GS} = 10 \text{ V}$
- Low gate charge (typical 31 nC)
- Low Crss (typical 14 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQB6N80 / FQI6N80	Units
V _{DSS}	Drain-Source Voltage		800	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		5.8	А
			3.67	А
I _{DM}	Drain Current - Pulsed	(Note 1)	23.2	А
V_{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		680	mJ
I _{AR}	Avalanche Current	(Note 1)	5.8	А
E _{AR}	Repetitive Avalanche Energy (Note		15.8	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.0	V/ns
P _D	Power Dissipation (T _A = 25°C) *		3.13	W
	Power Dissipation (T _C = 25°C)		158	W
	- Derate above 25°C		1.27	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.79	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

©2008 Fairchild Semiconductor International

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		800			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced t	to 25°C		0.9		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$				10	μΑ
		V _{DS} = 640 V, T _C = 125°C				100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	aracteristics			,			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 2.9 \text{ A}$			1.5	1.95	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 2.9 A	(Note 4)		5.9		S
C _{oss}	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V, } V_{GS} = 0 \text{ V,}$ f = 1.0 MHz			125 14	160 18	pF pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	V 400 V 1 5 0 A			30	70	ns
t _r	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 5.8 \text{ A},$ $R_{G} = 25 \Omega$ (Note 4, 5)			70	150	ns
t _{d(off)}	Turn-Off Delay Time				65	140	ns
t _f	Turn-Off Fall Time				45	100	ns
Qg	Total Gate Charge	V _{DS} = 640 V, I _D = 5.8 A, V _{GS} = 10 V			31		nC
Q _{gs}	Gate-Source Charge				7.1		nC
Q _{qd}	Gate-Drain Charge		(Note 4, 5)		15		nC
	Source Diode Characteristics a		i				
I _S	Maximum Continuous Drain-Source Did					5.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				23.2	Α	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 5.8 \text{ A}$				1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 5.8 \text{ A},$	(Note 4)		650		ns
Q_{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$	(Note 4)		5.7		μC

- 2. L = 38mH, I_{AS} = 5.8A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 5.8A, di/dt \leq 200A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

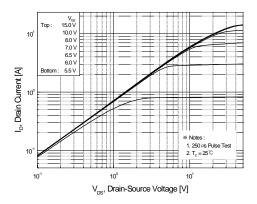


Figure 1. On-Region Characteristics

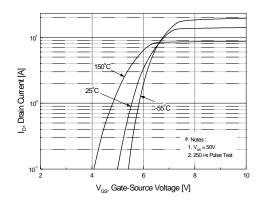


Figure 2. Transfer Characteristics

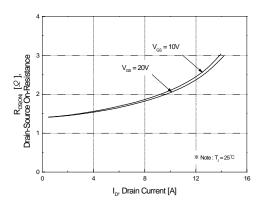


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

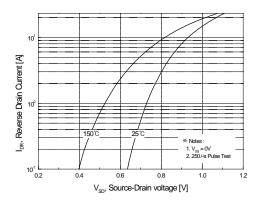


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

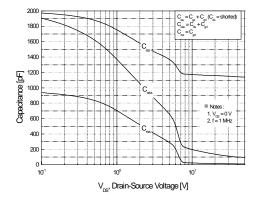


Figure 5. Capacitance Characteristics

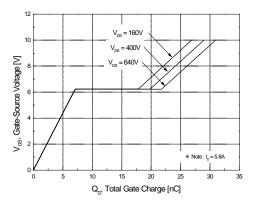
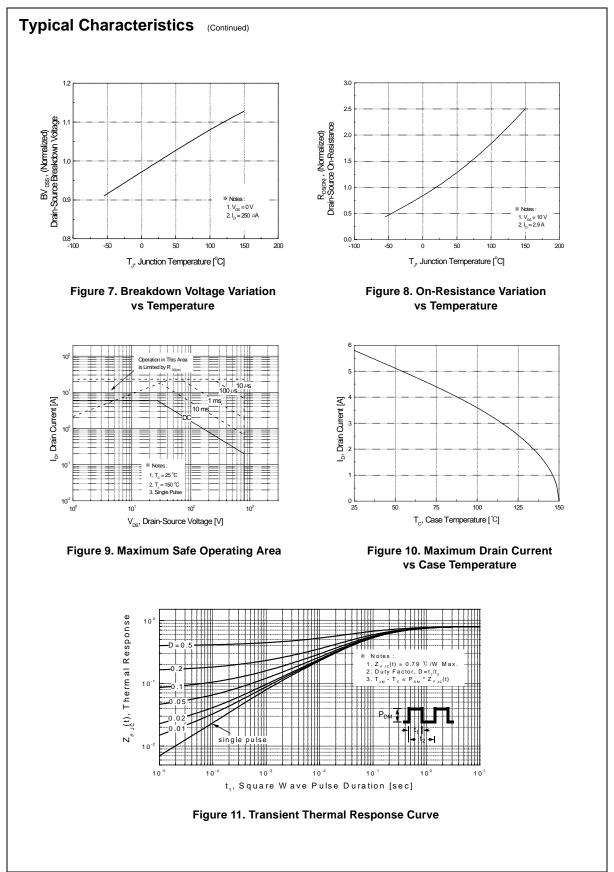


Figure 6. Gate Charge Characteristics

©2008 Fairchild Semiconductor International Rev. A1, Oct 2008



©2008 Fairchild Semiconductor International Rev. A1, Oct 2008

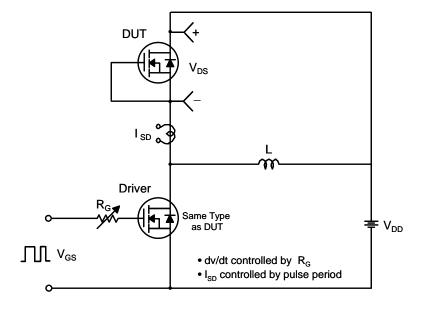
Gate Charge Test Circuit & Waveform V_{GS} Same Type as DUT 10V F V_{DS} DUT Charge **Resistive Switching Test Circuit & Waveforms** DUT **Unclamped Inductive Switching Test Circuit & Waveforms** $\mathsf{BV}_{\mathsf{DSS}}$ I_{AS} · V_{DD} $I_D(t)$ DUT V_{DD} V_{DS} (t)

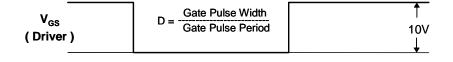
©2008 Fairchild Semiconductor International

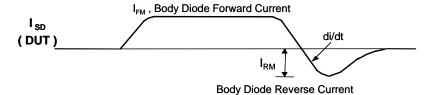
Time

Rev. A1, Oct 2008

Peak Diode Recovery dv/dt Test Circuit & Waveforms







V_{DS}
(DUT)

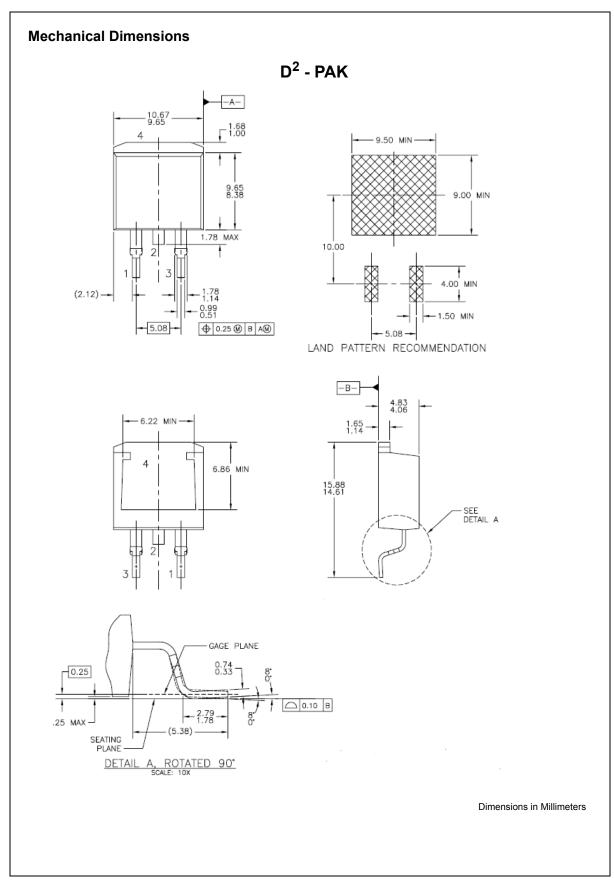
Body Diode Recovery dv/dt

V_{SD}

Body Diode

Forward Voltage Drop

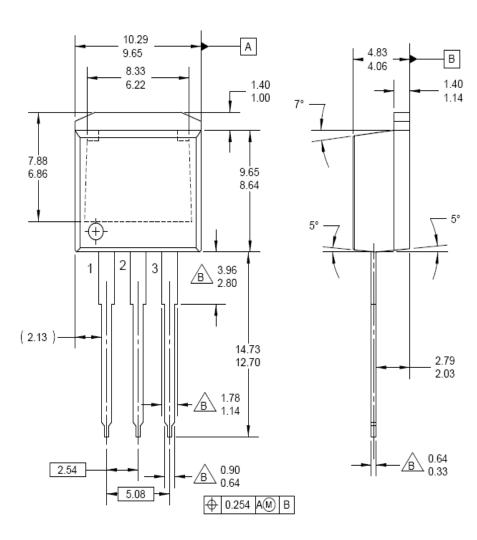
©2008 Fairchild Semiconductor International



©2000 Fairchild Semiconductor International

Mechanical Dimensions

I² - PAK



Dimensions in Millimeters

©2008 Fairchild Semiconductor International





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Build it Now™ CorePLUS™ CorePOWER™ $CROSSVOLT^{\text{TM}}$ CTL™ Current Transfer Logic™

EcoSPARK® EfficentMax™ EZSWITCH™ *

airchild®

Fairchild Semiconductor® FACT Quiet Series™

FACT® FAST® FastvCore™ FlashWriter® * FPS™ F-PFS™

FRFET® Global Power ResourceSM Green FPS™

Green FPS™ e-Series™ GTO™

IntelliMAX™ ISOPI ANAR™ MegaBuck™

MICROCOUPLER™

MicroFET™ MicroPak™ MillerDrive™ MotionMax™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS™

Programmable Active Droop™ QFET QSTM

Quiet Series™ RapidConfigure™

Saving our world, 1mW /W /kW at a time™ SmartMax™ SMART START™ SPM[®]

STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™

SYSTEM ® GENERAL The Power Franchise®

uwer P we TinyBoost™ TinyBuck™ TinyLogic[®] TIŃYOPTO™ TinyPower™ TinyPWM™ TinyWire™ μSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ XS™

* EZSWITCH™ and FlashWriter® are trademarks of System General Corporation, used under license by Fairchild Semiconductor

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

EIPE SUPPORT FOLICE.

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Farichild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Farichild strongly encourages customers to purchase Farichild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Farichild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I37

FQB6N80 / FQI6N80 Rev. A1 www.fairchildsemi.com